PATENT NUMBER

U.S. UTILITY Patent Application

M.S. O.I.P.E. PATEN PATENT DATE SCANNED &

APPLICATION NO. 09/833766	CONT/PRIOR	CLASS 029	SUBCLASS	ART UNIT 3729	Rodrigues	
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Pipe structure, alignment apparatus, electron beam lithography mapparatus, exposure apparatus, exposure apparatus maintenance method; semiconductor device manufacturing method, and semiconductor manufacturing factory

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ORIGINAL		. CROSS REFERENCE(S)							
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TERMINAL	DRAWINGS			CLAIMS ALLOWED		
DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.	
			1	NOTICE OF ALL	OWANCE MAILED	
The term of this patent subsequent to (date) has been disclaimed.	(Assistant	Examiner)	(Date)		•	
The term of this patent shall not extend beyond the expiration date of U.S Patent. No.	ŗ			ISS	JE FEE	
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